

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10510637	TAKAMINE ET AL.
	Examiner	Art Unit
	CHAU NGUYEN	2176

SEARCHED

Class	Subclass	Date	Examiner
715	200	03/30/2008	cn
715	234-236	03/30/2008	cn
715	243	03/30/2008	cn
715	255	03/30/2008	cn
715	273-274	03/30/2008	cn
715	200	10/07/2008	cn
715	234-236	10/07/2008	cn
715	243	10/07/2008	cn
715	255	10/07/2008	cn
715	273-274	10/07/2008	cn

SEARCH NOTES

Search Notes	Date	Examiner
Updated Search on East Reports	03/30/2008	cn
Updated Search on East Reports	10/07/2008	cn
Inventor Search for Double Patenting	10/07/2008	cn
NPL Search on IEEE Explorer	10/07/2008	cn

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner